## Notice of References Cited

Application/Control No. Applicant(s)/Patent Under Reexamination 10/537,139 VERSCHUREN ET AL. Examiner Art Unit Page 1 of 1 HENOK G. HEYI 2627

## II S PATENT DOCUMENTS

	U.S. PATENT DOCUMENTS						
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification		
*	Α	US-6,122,229 A	09-2000	Yonezawa, Seiji	369/13.08		
*	В	US-2005/0195716 A1	09-2005	Ko et al.	369/053.16		
*	С	US-7,230,893 B2	06-2007	Park, Yong Cheol	369/47.14		
	D	US-					
	Е	US-					
	F	US-					
	G	US-		-			
	Н	US-		-			
	-	US-					
	J	US-					
	к	US-					
	٦	US-					
	м	US-					

## FOREIGN PATENT DOCUMENTS

	FOREIGN PATENT DOCUMENTS							
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification		
	N	EP 913818 A1	05-1999	European Patent	OONUKI et al.	G11B 11/10		
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	Р							
	Q							
	R							
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	Т							

## NON DATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
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